AFM Probe Specifications:
Coating
Magnetic
Additional Info
The 240AC-MA AFM probes are designed for Magnetic Force Microscopy (MFM) measurements.
The tetrahedral AFM tip is located precisely at the free end of the AFM cantilever. This allows the AFM tip to be positioned accurately over the area of interest on the sample surface.
The hard magnetic AFM tip side coating ensures high magnetic force sensitivity and resolution. The back side aluminum coating significantly enhances the AFM cantilever reflectivity in air and vacuum.

AFM Tip:

Shape	Height	Setback	Radius	Half Cone Angle
Optimized Positioning	14 µm (12 - 16 µm)*	0 µm	< 60 nm	0° front, 35° back, <9° side

* typical values

AFM Cantilever:

Cantilever	Shape	Force Const.	Res. Freq.	Lenght	Width	Thickness
Soft tapping mode AFM cantilever	Beam	2 N/m (0.6 - 3.9 N/m)*	70 kHz (45 - 90 kHz)*	240 µm (1 - 250µm)*	40 µm (38 - 42µm)*	2.6µm (2.1 - 3.1 µm)*

* typical values